

## Freeform Search

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<b>Database:</b>	US Pre-Grant Publication Full-Text Database US Patents Full-Text Database US OCR Full-Text Database EPO Abstracts Database JPO Abstracts Database Derwent World Patents Index IBM Technical Disclosure Bulletins
<b>Term:</b>	L3 and (reus\$4 or recycl\$3 or repeat\$3 or reclaim\$5)
<b>Display:</b>	<input type="text" value="10"/> Documents in <b>Display Format:</b> <input type="text" value="-"/> Starting with Number <input type="text" value="1"/>
<b>Generate:</b> <input type="radio"/> Hit List <input checked="" type="radio"/> Hit Count <input type="radio"/> Side by Side <input type="radio"/> Image	

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### Search History

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**DATE:** Monday, April 25, 2005   
 [Printable Copy](#)   
 [Create Case](#)

<u>Set</u> <u>Name</u> <u>Query</u>	<u>Hit</u> <u>Count</u>	<u>Set</u> <u>Name</u> result set
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPL,TDBD; PLUR=YES; OP=OR</i>		
<u>L4</u> L3 and (reus\$4 or recycl\$3 or repeat\$3 or reclaim\$5)	69	<u>L4</u>
<u>L3</u> L1 and (smart adj cut)	148	<u>L3</u>
<u>L2</u> L1 and residue	88	<u>L2</u>
<u>L1</u> (wafer with bond\$3) and (wafer with (separat\$3 or delaminat\$4 or detach\$5 or split\$4)) and implant\$5 and (polish\$4 or CMP) and (rough\$4 or uniform\$3 or non-uniform\$3 or nonuniform\$3 or smooth\$4)	888	<u>L1</u>

END OF SEARCH HISTORY